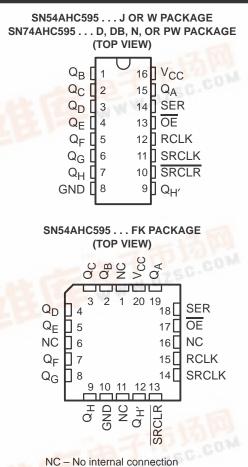
查询SN54AHC595供应商

- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V_{CC}
- 8-Bit Serial-In, Parallel-Out Shift
- Shift Register Has Direct Clear
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

description

The 'AHC595 devices contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state outputs. Separate clocks are provided for both the shift and storage registers. The shift register has a direct overriding clear (SRCLR) input, serial (SER) input, and a serial output for cascading. When the output-enable (\overline{OE}) input is high, all outputs, except $Q_{H'}$, are in the high-impedance state.

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Both the shift-register clock (SRCLK) and storage-register clock (RCLK) are positive-edge triggered. If both clocks are connected together, the shift register always is one clock pulse ahead of the storage register.

The SN54AHC595 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74AHC595 is characterized for operation from -40° C to 85° C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

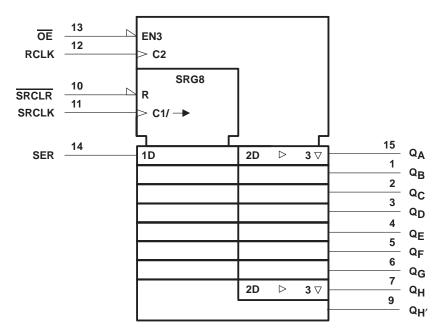
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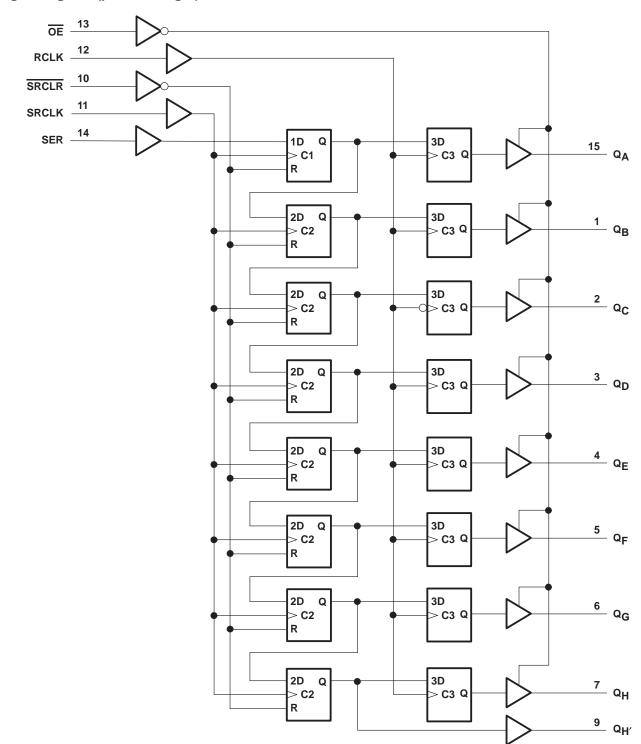
				Fl	JNCTION TABLE
		INPUTS			FUNCTION
SER	SRCLK	SRCLR	RCLK	OE	FONCTION
Х	Х	Х	Х	Н	Outputs Q _A –Q _H are disabled.
Х	Х	Х	Х	L	Outputs Q _A –Q _H are enabled.
Х	Х	L	Х	Х	Shift register is cleared.
L	Ŷ	Н	Х	Х	First stage of the shift register goes low. Other stages store the data of previous stage, respectively.
н	Ŷ	Н	х	Х	First stage of the shift register goes high. Other stages store the data of previous stage, respectively.
Х	\downarrow	Н	Х	Х	Shift-register state is not changed.
Х	Х	Х	\uparrow	Х	Shift-register data is stored into the storage register.
Х	Х	Х	\downarrow	Х	Storage-register state is not changed.

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, N, PW, and W packages.





logic diagram (positive logic)

Pin numbers shown are for the D, DB, J, N, PW, and W packages.



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timing	diagram
SRCLK	
SER	
RCLK	
SRCLR	
ŌE	
Q _A	
QB	
QC	
QD	
QE	
QF	
QG	
QH	
Q _H ,	



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Input voltage range, V _I (see Note 1) Output voltage range, V _O (see Note 1) Input clamp current, I _{IK} (V _I < 0) Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) Continuous output current, I _O (V _O = 0 to V _{CC}) Continuous current through V _{CC} or GND Package thermal impedance, θ_{JA} (see Note 2): D par DB p N par PW p	-0.5 V to 7 V -0.5 V to 7 V -0.5 V to 7 V -0.5 V to V _{CC} + 0.5 V -20 mA ±20 mA ±25 mA ±25 mA ±75 mA ckage 113°C/W ackage 78°C/W backage 149°C/W -65°C to 150°C
Storage temperature range, Istg	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

			SN54A	HC595	SN74A	HC595	LINUT	
			MIN	MAX	MIN	MAX	UNIT	
VCC	Supply voltage		2	5.5	2	5.5	V	
		V _{CC} = 2 V	1.5		1.5			
V_{IH}	High-level input voltage	V _{CC} = 3 V	2.1		2.1		V	
		V _{CC} = 5.5 V	3.85		3.85			
		$V_{CC} = 2 V$		0.5		0.5		
VIL	Low-level input voltage	V _{CC} = 3 V		0.9		0.9	V	
			1.65		1.65			
VI	Input voltage	-	0	5.5	0	5.5	V	
Vo	Output voltage		Q.	Vcc	0	VCC	V	
		$V_{CC} = 2 V$	202	-50		-50	μA	
ЮН	High-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	4	-4		-4		
		V_{CC} = 5 V ± 0.5 V	~	-8		-8	mA	
		$V_{CC} = 2 V$		50		50	μA	
IOL	Low-level output current	V_{CC} = 3.3 V ± 0.3 V		4		4	mA	
		V_{CC} = 5 V ± 0.5 V		8		8	mA	
A #/ A	Input transition rise or fell rate	V_{CC} = 3.3 V ± 0.3 V		100		100	n n//	
$\Delta t / \Delta v$	Input transition rise or fall rate $V_{CC} = 5 V \pm 0.5$			20		20	ns/V	
TA	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	N	Т	ן = 25°C	;	SN54AH	HC595	SN74A	HC595	UNIT	
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
		2 V	1.9	2		1.9		1.9			
	I _{OH} = -50 μA	3 V	2.9	3		2.9		2.9			
∨он		4.5 V	4.4	4.5		4.4		4.4		V	
	$I_{OH} = -4 \text{ mA}$	3 V	2.58			2.48		2.48			
	I _{OH} = -8 mA	4.5 V	3.94			3.8	h	3.8			
		2 V			0.1		0.1		0.1		
	I _{OL} = 50 μA	3 V			0.1		0.1		0.1	1	
VOL		4.5 V			0.1	~	0.1		0.1	V	
	I _{OL} = 4 mA	3 V			0.36	JUC C	0.5		0.44		
	I _{OL} = 8 mA	4.5 V			0.36	20	0.5		0.44		
Ц	$V_{I} = V_{CC}$ or GND	0 V to 5.5 V			±0.1	2	±1*		±1	μΑ	
loz	$\frac{V_{I}}{OE} = V_{CC} \text{ or GND}, V_{O} = V_{CC} \text{ or GND}, $	5.5 V			±0.25		±2.5		±2.5	μΑ	
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			4		40		40	μA	
Ci	$V_I = V_{CC}$ or GND	5 V		3	10				10	pF	
Co	$V_{O} = V_{CC}$ or GND	5 V		5.5						pF	

* On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0$ V.

timing requirements over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

			T _A =	25°C	SN54A	HC595	SN74A	HC595	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		SRCLK high or low	5		5		5		
tw	Pulse duration	RCLK high or low	5		5	EN	5		ns
		SRCLR low	5		5	EN	5		
		SER before SRCLK↑	3.5		3.5	4	3.5		
	O a true time a	SRCLK [↑] before RCLK ^{↑†}	8		8.5	2	8.5		
t _{su}	Setup time	SRCLR low before RCLK [↑]	8		39		9		ns
		SRCLR high (inactive) before SRCLK1	3		\$ 3		3		
t _h	Hold time	SER after SRCLK↑	1.5		1.5		1.5		ns

[†] This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.



timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

			T _A = 1	25°C	SN54A	HC595	SN74A	HC595	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
		SRCLK high or low	5		5		5		
tw	Pulse duration	RCLK high or low	5		5	EW	5		ns
		SRCLR low	5		5	EL	5		
		SER before SRCLK [↑]	3		3	L'	3		
+	Catura tima	SRCLK [↑] before RCLK ^{↑†}	5		5	r.	5		ns
t _{su}	Setup time	SRCLR low before RCLK [↑]	5		36		5		115
		SRCLR high (inactive) before SRCLK↑	2.5		2.5		2.5		
t _h	Hold time	SER after SRCLK [↑]	2		2		2		ns

[†] This setup time allows the storage register to receive stable data from the shift register. The clocks can be tied together, in which case the shift register is one clock pulse ahead of the storage register.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

	FROM	то	LOAD	T,	A = 25°C	;	SN54A	HC595	SN74A	HC595	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
f			C _L = 15 pF	80*	120*		70*		70		MHz
fmax			CL = 50 pF	55	105		50		50		IVILL
^t PLH	DOLK	0.0	C _L = 15 pF		6*	11.9*	1*	13.5*	1	13.5	ns
^t PHL	RCLK	Q _A –Q _H	CL = 15 pr		6*	11.9*	1*	13.5*	1	13.5	115
^t PLH		0	Ci - 15 pE		6.6*	13*	1*	15*	1	15	ns
^t PHL	SRCLK	Q _H ′	C _L = 15 pF		6.6*	13*	1*	15*	1	15	ns
^t PHL	SRCLR	Q _H ′	CL = 15 pF		6.2*	12.8*	1*	13.7*	1	13.7	ns
^t PZH			0. 45		6*	11.5*	1*	13.5*	1	13.5	
^t PZL	OE	Q _A –Q _H	C _L = 15 pF		7.8*	11.5*	1*,4	13.5*	1	13.5	ns
^t PLH	DOI 14		C: 50 pF		7.9	15.4	D.	17	1	17	
^t PHL	RCLK	Q _A –Q _H	C _L = 50 pF		7.9	15.4	Q1	17	1	17	ns
^t PLH	00011/	-	C ₁ = 50 pF		9.2	16.5	S 1	18.5	1	18.5	
^t PHL	SRCLK	Q _H ′	CL = 50 pr		9.2	16.5	1	18.5	1	18.5	ns
^t PHL	SRCLR	Q _H ′	CL = 50 pF		9	16.3	1	17.2	1	17.2	ns
^t PZH			0. 50 - 5		7.8	15	1	17	1	17	
^t PZL	OE	Q _A –Q _H	C _L = 50 pF		9.6	15	1	17	1	17	ns
^t PHZ	OE	0.00	0. 50 - 5		8.1	15.7	1	16.2	1	16.2	
^t PLZ	UE	Q _A –Q _H	C _L = 50 pF		9.3	15.7	1	16.2	1	16.2	ns

* On products compliant to MIL-PRF-38535, this parameter is not production tested.



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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD	T,	₄ = 25° Ω	>	SN54Ał	HC595	SN74A	HC595	115117
FARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
4			CL = 15 pF	135*	170*		115*		115		MHz
fmax			C _L = 50 pF	95	140		85		85		
^t PLH	RCLK	0.000	C _I = 15 pF		4.3*	7.4*	1*	8.5*	1	8.5	ns
^t PHL	RCLK	K $Q_A - Q_H$ $C_L = 15 pF$		4.3*	7.4*	1*	8.5*	1	8.5	115	
^t PLH	SPOLK	0	C _I = 15 pF		4.5*	8.2*	1*	9.4*	1	9.4	ns
^t PHL	SRCLK	Q _H ′	0[= 10 pi		4.5*	8.2*	1*	9.4*	1	9.4	115
^t PHL	SRCLR	Q _H ′	C _L = 15 pF		4.5*	8*	1*	9.1*	1	9.1	ns
^t PZH	OE		C _I = 15 pF		4.3*	8.6*	1*	10*	1	10	ns
^t PZL	OE	Q _A –Q _H			5.4*	8.6*	1*,4	10*	1	10	10
^t PLH	DOLK	0.0	C _I = 50 pF		5.6	9.4	0	10.5	1	10.5	ns
^t PHL	RCLK	Q _A –Q _H	CL = 50 pr		5.6	9.4	Q1	10.5	1	10.5	115
^t PLH	SPCLK	0	C _I = 50 pF		6.4	10.2	x 1	11.4	1	11.4	ns
^t PHL	SRCLK	Q _H ′	0 <u> </u>		6.4	10.2	1	11.4	1	11.4	115
^t PHL	SRCLR	Q _H ′	C _L = 50 pF		6.4	10	1	11.1	1	11.1	ns
^t PZH			C ₁ = 50 pF		5.7	10.6	1	12	1	12	
^t PZL	OE	Q _A –Q _H	0L = 50 pr		6.8	10.6	1	12	1	12	ns
^t PHZ	OE	0.00	C ₁ = 50 pF		3.5	10.3	1	11	1	11	ns
^t PLZ	UE	Q _A –Q _H			3.4	10.3	1	11	1	11	115

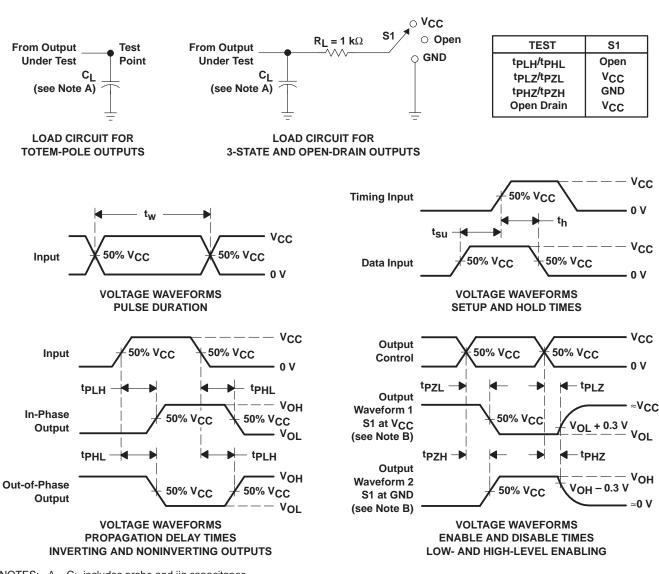
* On products compliant to MIL-PRF-38535, this parameter is not production tested.

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load, f = 1 MHz	25.2	pF



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CI includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_Q = 50 Ω , t_f \leq 3 ns, t_f \leq 3 ns.

D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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